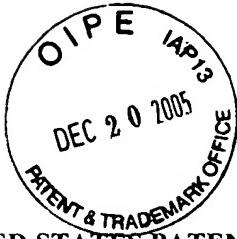


Docket No.: 057454-0972

IPW
PATENT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Hideto HIDAKA : Confirmation Number: 2444
Application No.: 10/663,674 : Group Art Unit: 2824
Filed: September 17, 2003 : Examiner: PHUNG, ANH

For: THIN FILM MAGNETIC MEMORY DEVICE HAVING DATA READ CURRENT TUNING FUNCTION

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

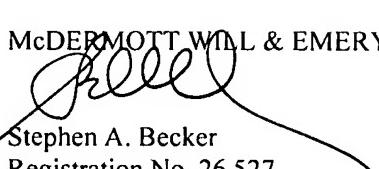
This Information Disclosure Statement is being filed under Rule 37 CFR 1.97(i), wherein applicants are submitting references and Office Action (w/English Translation), before the grant of a patent to be placed in the file.

Accordingly, copies of the references as listed on the attached Form PTO-1449 are submitted herewith for placement in the file. No certification or fees are deemed necessary.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP


Stephen A. Becker
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Facsimile: 202.756.8087
Date: December 20, 2005

Please recognize our Customer No. 20277 as
our correspondence address.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)		ATTY. DOCKET NO. 057454-0972		SERIAL NO. 10/663,674		
		APPLICANT Hideto HIDAKA				
		FILING DATE September 17, 2003	GROUP 2824			
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code ₃ -Number 4-Kind Codes (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
		BOEVE, H., et al. "Electrical characteristics of magnetic memory cells comprising magnetic tunnel junctions and GaAs diodes." Electronics Letters, Volume 36, Number 21, October 12, 2000, pp. 1782-1783				
		RODRIGUEZ, R., et al. "Analysis of the degradation and breakdown of thin SiO₂ films under static and dynamic tests using a two-step stress procedure." IEEE Transactions on Electro Devices, Volume 47, Number 11, November 2000, pp. 2138-2145				
EXAMINER			DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.